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**Nizkonapetostne stikalne in krmilne naprave - 10. del: Polprevodniški odklopniki  
(IEC 60947-10:2026)**

Low-voltage switchgear and controlgear - Part 10: Semiconductor circuit-breakers (IEC 60947-10:2026)

Niederspannungsschaltgeräte – Teil 10: Halbleiter-Leistungsschalter (IEC 60947-10:2026)

Appareillage à basse tension - Partie 10: Disjoncteurs à semi-conducteurs (IEC 60947-10:2026)

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**Low-voltage switchgear and controlgear - Part 10:  
Semiconductor circuit-breakers  
(IEC 60947-10:2026)**

Appareillage à basse tension - Partie 10: Disjoncteurs à  
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Niederspannungsschaltgeräte - Teil 10: Halbleiter-  
Leistungsschalter  
(IEC 60947-10:2026)

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**EN IEC 60947-10:2026 (E)****European foreword**

The text of document 121A/712/FDIS, future edition 1 of IEC 60947-10, prepared by SC 121A "Low-voltage switchgear and controlgear" of IEC/TC 121 "Switchgear and controlgear and their assemblies for low voltage" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60947-10:2026.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2027-07-31 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2029-07-31 document have to be withdrawn

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This document is read in conjunction with EN IEC 60947-1:2021.

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## Endorsement notice

The text of the International Standard IEC 60947-10:2026 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 60335-1:2020	NOTE	Approved as EN IEC 60335-1:2023 (not modified) +A11:2023
IEC 60947-4-1:2023	NOTE	Approved as EN IEC 60947-4-1:2025 (not modified)
IEC 61000-4-13	NOTE	Approved as EN 61000-4-13
IEC 61508-1:2010	NOTE	Approved as EN 61508-1:2010 (not modified)
IEC/TR 63201	NOTE	Approved as CLC IEC/TR 63201
IEC 63208	NOTE	Approved as EN IEC 63208

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cencenelec.eu](http://www.cencenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-6	-	Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	-
IEC 60068-2-14	-	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN IEC 60068-2-14	-
IEC 60068-2-30	-	Environmental testing - Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN IEC 60068-2-30	-
IEC 60664-1	2020	Insulation coordination for equipment within low-voltage supply systems - Part 1: Principles, requirements and tests	EN IEC 60664-1	2020
IEC 60695-2-11	2021	Fire hazard testing - Part 2-11: Glowing/hot-wire based test methods - Glow-wire flammability test method for end products (GWEPT)	EN IEC 60695-2-11	2021
IEC 60747-9	-	Semiconductor devices - Part 9: Discrete devices - Insulated-gate bipolar transistors (IGBTs)	-	-
IEC 60749-5	-	Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test	EN IEC 60749-5	-
IEC 60749-23	-	Semiconductor devices - Mechanical and climatic test methods - Part 23: High temperature operating life	EN IEC 60749-23	-
IEC 60749-25	-	Semiconductor devices - Mechanical and climatic test methods - Part 25: Temperature cycling	EN 60749-25	-
IEC 60749-34	-	Semiconductor devices - Mechanical and climatic test methods - Part 34: Power cycling	EN 60749-34	-
IEC 60947-1	2020	Low-voltage switchgear and controlgear - Part 1: General rules	EN IEC 60947-1	2021

**EN IEC 60947-10:2026 (E)**

IEC 60947-2	2024	Low-voltage switchgear and controlgear - Part 2: Circuit-breakers	EN IEC 60947-2	2025
IEC 61000-3-2	-	Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current $\leq 16$ A per phase)	EN IEC 61000-3-2	-
IEC 61000-3-3	-	Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current $\leq 16$ A per phase and not subject to conditional connection	EN 61000-3-3	-
IEC 61000-4-2	2025	Electromagnetic compatibility (EMC) - Part 4-2: Testing and measurement techniques - Electrostatic discharge immunity test	EN IEC 61000-4-2	2025
IEC 61000-4-3	2020	Electromagnetic compatibility (EMC) - Part 4-3: Testing and measurement techniques - Radiated, radio-frequency, electromagnetic field immunity test	EN IEC 61000-4-3	2020
IEC 61000-4-4	2012	Electromagnetic compatibility (EMC) - Part 4-4: Testing and measurement techniques - Electrical fast transient/burst immunity test	EN 61000-4-4	2012
IEC 61000-4-5	2014	Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test	EN 61000-4-5	2014
IEC 61000-4-6	2023	Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields	EN IEC 61000-4-6	2023
IEC 61000-4-11	-	Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current up to 16 A per phase	EN IEC 61000-4-11	-
IEC 61000-4-29	-	Electromagnetic compatibility (EMC) - Part 4-29: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests	EN 61000-4-29	-
IEC 61000-4-34	-	Electromagnetic compatibility (EMC) - Part 4-34: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current more than 16 A per phase	EN 61000-4-34	-
IEC 61508-1	2010	Functional safety of electrical/electronic/programmable electronic safety-related systems - Part 1: General requirements	EN 61508-1	2010

IEC 61508-3	2010	Functional safety of electrical/electronic/programmable electronic safety-related systems - Part 3: Software requirements	EN 61508-3	2010
IEC 61709	-	Electric components - Reliability - Reference conditions for failure rates and stress models for conversion	EN 61709	-
IEC 62475	2010	High-current test techniques - Definitions and requirements for test currents and measuring systems	EN 62475	2010
CISPR 11	2024	Industrial, scientific and medical equipment - Radio-frequency disturbance characteristics - Limits and methods of measurement	EN IEC 55011	2025
AEC-Q101		Failure mechanism based stress test qualification for discrete semiconductors in automotive applications		
JEDEC JESD47		Stress-test-driven qualification of integrated circuit		
UL 991:2024		Tests for Safety-Related Controls Employing Solid-State Devices		

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# INTERNATIONAL STANDARD

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**Low-voltage switchgear and controlgear -  
Part 10: Semiconductor circuit-breakers**

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